National Semiconductor

MM2114/MM2114L Family 4096-Bit (1024 × 4) Static RAMs

Maximum Access/Current	MM2114-15L	MM2114-2L	MM2114-25L	MM2114-3L	MM2114-L	MM2114-15	MM2114-2	MM2114-25	MM2114-3	MM2114
Access (TAVQV-ns)	150	200	250	300	450	150	200	250	300	450
Active Current (I_{CC}-mA)	70	70	70	70	70	100	100	100	100	100

General Description

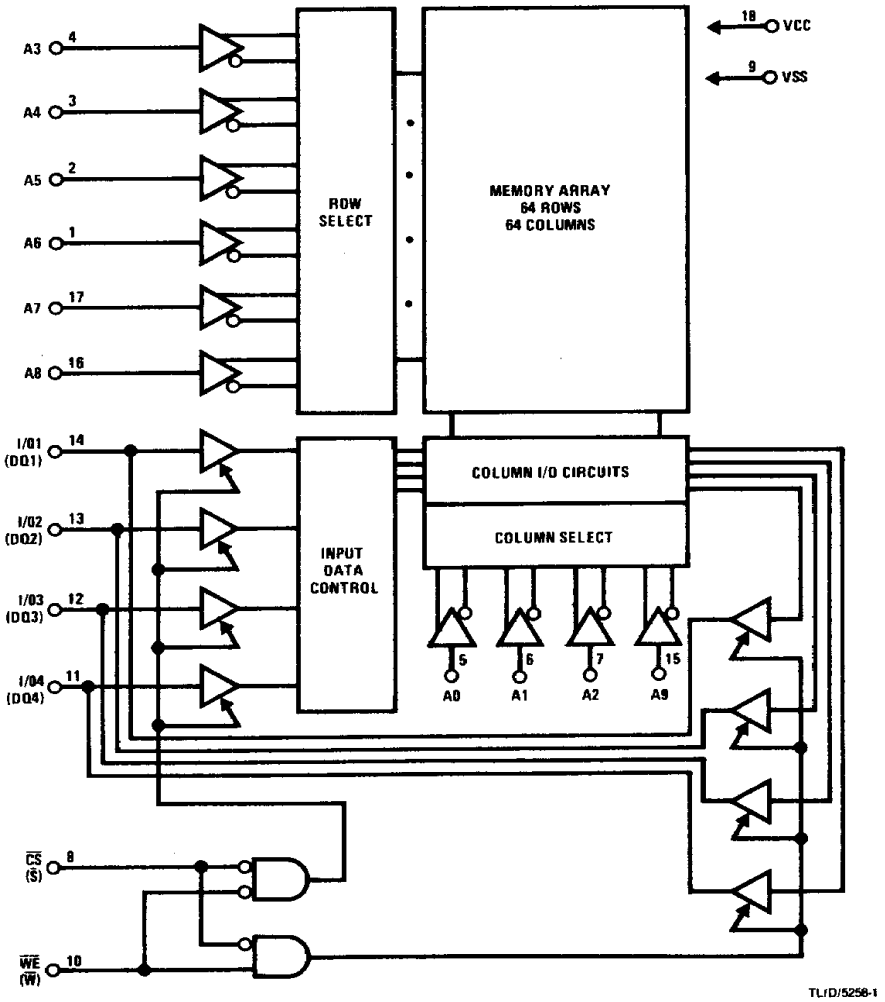
The MM2114 family of 1024-word by 4-bit static random access memories is fabricated using N-channel silicon-gate technology. All internal circuits are fully static and therefore require no clocks or refreshing for operation. The data is read out nondestructively and has the same polarity as the input data. Common input/output pins are provided.

The separate chip select input ($\overline{CS}$) allows easy memory expansion by OR-tying individual devices to a data bus.

Features

- All inputs and outputs directly TTL compatible
- Static operation—no clocks or refreshing required
- Low power—225 mW typical
- High speed—down to 150 ns access time
- TRI-STATE® output for bus interface
- Common Data In and Data Out pins
- Single 5V supply
- Standard 18-pin dual-in-line package
- Available with MIL-STD-883 class B screening

Block Diagram*



* Symbols in parentheses are proposed industry standard.

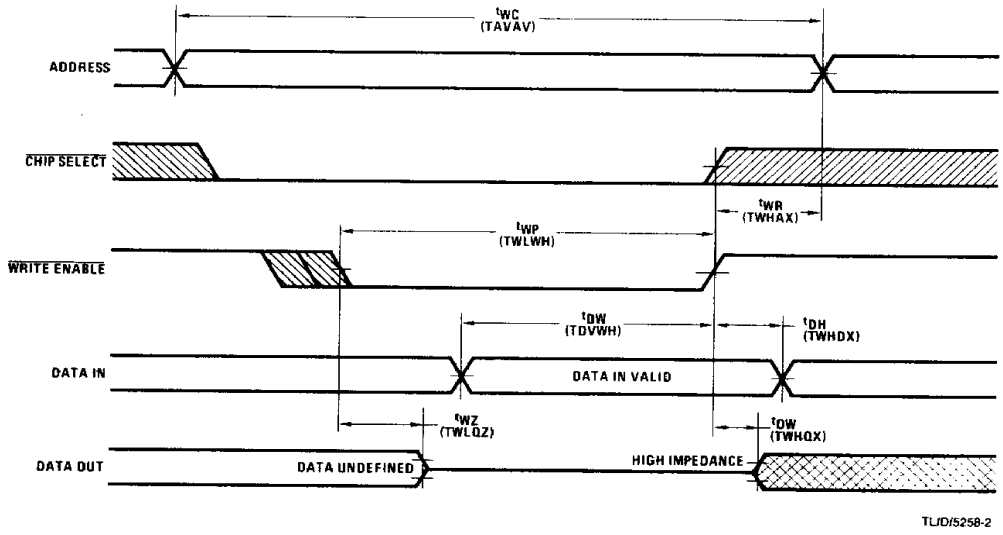
Write Cycle AC Electrical Characteristics (Note 3) $T_A = 0°C$ to $+70°C$, $V_{CC} = 5V \pm 5\%$

Symbol		Parameter	MM2114-15 MM2114-15L		MM2114-2 MM2114-2L		MM2114-25 MM2114-25L		MM2114-3 MM2114-3L		MM2114 MM2114-L		Units
Alternate	Standard		Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	
t_{WC}	TAVAV	Write Cycle Time	150		200		250		300		450		ns
t_{WP}	TWLWH	Write Pulse Width	90		100		125		150		200		ns
t_{WR}	TWHAX	Write Recovery Time	0		0		0		0		0		ns
t_{DW}	TDVWH	Data Set-Up Time	90		100		125		150		200		ns
t_{DH}	TWHDX	Data Hold Time	0		0		0		0		0		ns
t_{WZ}	TWLQZ	Write Enable to Output TRI-STATE (Note 5)	0	40	0	40	0	60	0	80	0	100	ns
t_{OW}	TWHQX	Output Active from End of Write ($\overline{WE}$) (Note 5)		80		80		90		100		120	ns

*Symbols in parentheses are proposed industry standard.

Write Cycle Waveforms* (Note 4)

Write Cycle 1 (Write Enable Limited)



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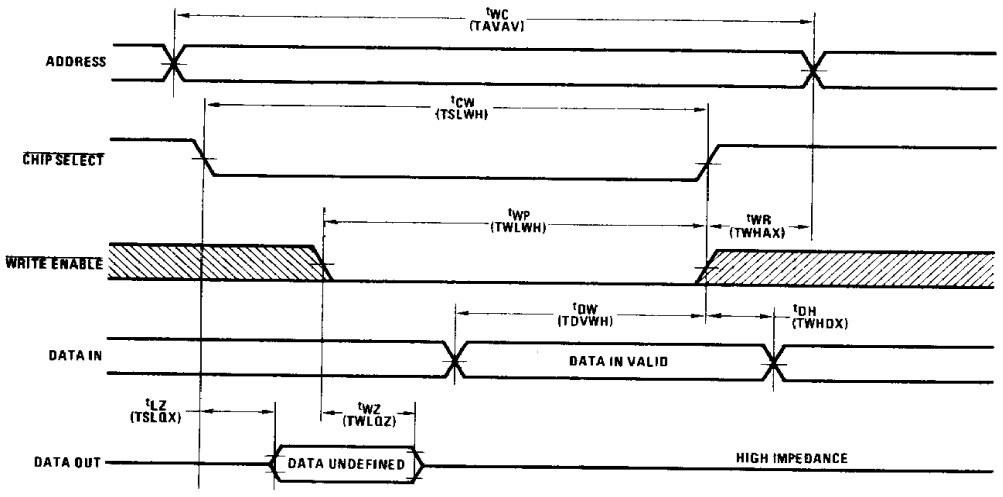
Write Cycle 2 (Chip Select Limited)



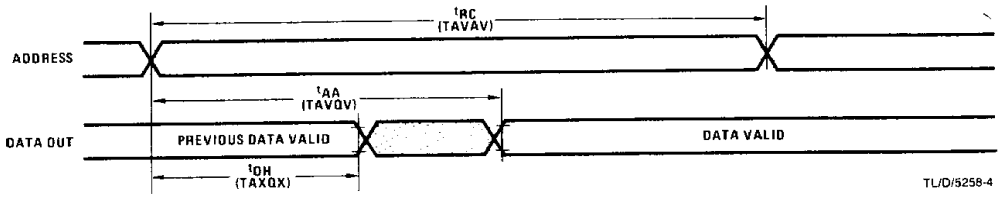
TL/D/5258-3

Read Cycle AC Electrical Characteristics $T_A = 0°C$ to $+70°C$, $V_{CC} = 5V \pm 5\%$

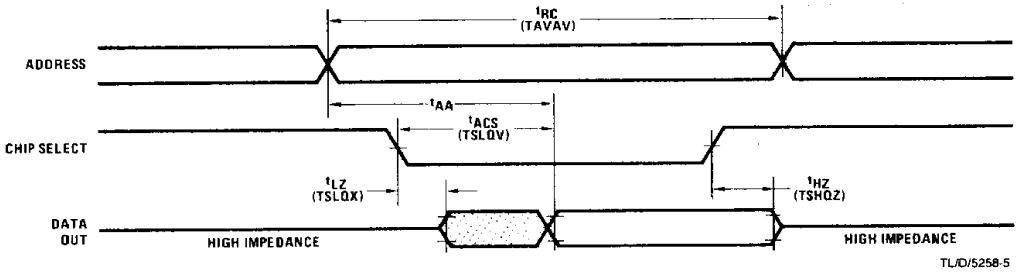
Symbol		Parameter	MM2114-15 MM2114-15L		MM2114-2 MM2114-2L		MM2114-25 MM2114-25L		MM2114-3 MM2114-3L		MM2114 MM2114-L		Units
Alternate	Standard		Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	
t_{RC}	TAVAV	Read Cycle Time ($\overline{WE} = V_{IH}$)	150		200		250		300		450		ns
t_{AA}	TAVQV	Address Access Time		150		200		250		300		450	ns
t_{ACS}	TSLQV	Chip Select Access Time		70		70		90		100		120	ns
t_{LZ}	TSLQX	Chip Select to Output Active (Note 5)	20		20		20		20		20		ns
t_{HZ}	TSHQZ	Chip Deselect to Output TRI-STATE (Note 5)	0	40	0	40	0	60	0	80	0	100	ns
t_{OH}	TAXQX	Output Hold from Address Change	15		10		10		10		10		ns

Read Cycle Waveforms*

Read Cycle 1 (Continuous Selection $\overline{CS} = V_{IL}$, $\overline{WE} = V_{IH}$)



Read Cycle 2 (Chip Select Switched, $\overline{WE} = V_{IH}$)



Note 3: A write occurs during the coincidence low of $\overline{CS}$ and $\overline{WE}$.

Note 4: The output remains TRI-STATE if the $\overline{CS}$ and $\overline{WE}$ go high simultaneously. $\overline{WE}$ or $\overline{CS}$ or both must be high during the address transitions.

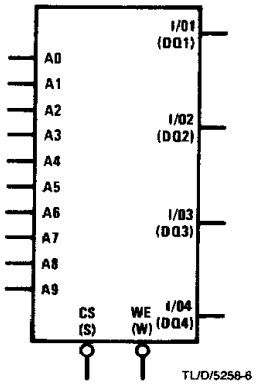
Note 5: Measured ± 50 mV from steady state voltage. This parameter is sampled and not 100% tested.

DC Electrical Characteristics $T_A = 0°C$ to $+70°C$, $V_{CC} = 5V \pm 5\%$

Symbol	Parameter	Conditions	MM2114, MM2114-15, MM2114-2, MM2114-25, MM2114-3		MM2114-L, MM2114-15L, MM2114-2L, MM2114-25L, MM2114-3L		Units
			Min	Max	Min	Max	
I_{LI}	Input Load Current (All Input Pins)	$V_{IN} = 0V$ to $5.25V$	−10	10	−10	10	μA
I_{LO}	Output Leakage Current	$\overline{CS} = V_{IH}$, $V_{OUT} = 0.4V$ to $4V$	−10	10	−10	10	μA
V_{IL}	Input Low Voltage		−0.5	0.8	−0.5	0.8	V
V_{IH}	Input High Voltage		2.0	V_{CC}	2.0	V_{CC}	V
V_{OL}	Output Low Voltage	$I_{OL} = 2.1$ mA		0.4		0.4	V
V_{OH}	Output High Voltage	$I_{OH} = -1.0$ mA	2.4		2.4		V
I_{CC}	Power Supply Current	$V_{IN} = 5.25V$, $T_A = 0°C$ Outputs Open		100		70	mA

* The symbols in parentheses are proposed industry standard.

Logic Symbol*

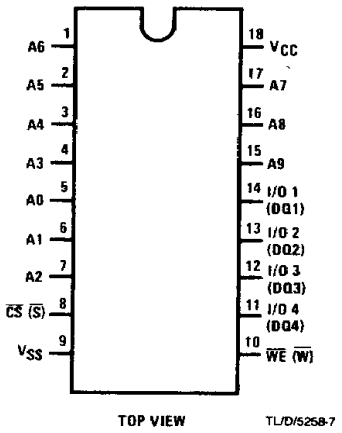


Pin Names*

A0–A9	Address Inputs
$\overline{WE}$ ($\overline{W}$)	Write Enable
$\overline{CS}$ ($\overline{S}$)	Chip Select
I/01–I/04 (DQ1–DQ4)	Data Input/Output

Connection Diagram*

Dual-In-Line Package



Order Number MM2114N-15L, MM2114N-15, MM2114N-2L, MM2114N-2, MM2114N-3L, MM2114N-3, MM2114N-L or MM2114N
NS Package Number N18A

Absolute Maximum Ratings

Voltage at Any Pin	−0.5V to +7V
Storage Temperature	−65°C to −150°C
Power Dissipation	1W
Lead Temperature (Soldering, 10 seconds)	300°C

Operating Conditions

	Min	Max	Units
Supply Voltage (V_{CC})	4.75	5.25	V
Ambient Temperature (T_A)	0	+70	°C

Capacitance $T_A = 25°C$, f = 1 MHz (Note 1)

Symbol	Parameter	Conditions	MM2114, MM2114-15, MM2114-2, MM2114-25, MM2114-3		MM2114-L, MM2114-15L, MM2114-2L, MM2114-25L, MM2114-3L		Units
			Min	Max	Min	Max	
C_{IN}	Input Capacitance	All Inputs $V_{IN} = 0V$		5		5	pF
C_{OUT} (Note 2)	Output Capacitance	$V_O = 0V$		5		5	pF

Note 1: This parameter is guaranteed by periodic testing.
Note 2: C_{OUT} is max 10 pF for (J) package.

AC Test Conditions

Input Pulse Levels	0V to 3V	Output Load and Timing Levels	0.8V @ 2.1 mA + 100 pF 2.0V @ −1.0 mA + 100 pF
Input Rise and Fall Times	≤ 10 ns		
Input Timing Level	1.5V		

*Symbols in parentheses are proposed industry standard.